



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16864Generic Copy

Issue Date: 08-Jun-2012**TITLE:** VHVIC 2nd Source Qualification to Gresham FAB – Phase 4**PROPOSED FIRST SHIP DATE:** 08-Sep-2012**AFFECTED CHANGE CATEGORY(S):** Wafer FAB location**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**Contact your local ON Semiconductor Sales Office or <Scott.Brow@onsemi.com>**SAMPLES:** Contact your local ON Semiconductor Sales Office**ADDITIONAL RELIABILITY DATA:** AvailableContact your local ON Semiconductor Sales Office or <Ken.Fergus@onsemi.com>**NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.**DESCRIPTION AND PURPOSE:**

The purpose of this final PCN is to notify customers of the platform qualification of a second source for the devices listed in this FPCN at ON Semiconductor's wafer fabrication facilities in Gresham, Oregon.

This qualification is being made to increase the capacity for this technology. This technology is currently produced out of ON Semiconductor's wafer fabrication facilities in Aizu, Japan

The VHVIC1 process is being duplicated at the Gresham wafer FAB. No die design changes have occurred. No changes to the device performance, data sheets or packaging have been made.

**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16864****RELIABILITY DATA SUMMARY:****Reliability Test Results:**

NCP1203/NCP1217					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTBB	TA=125C, 500V Bias	Test @ 1008hrs	3 lots x 80 units	0/239*
2	HTOL	TA=125C, 200V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
3	HTSL	TA=150C	Test @ 1008hrs	3 lots x 80 units	0/240
4	PC-TC	-65C to +150C	Test @ 500 Cycles	3 lots x 80 units	0/240
5	PC-AC	TA=121C, RH=100%, PSI=15	Test @ 96hrs	3 lots x 80 units	0/240
6	PC-UHAST	TA=130C, RH=85%, PSI=18.8 no Bias	Test @ 96hrs	3 lots x 80 units	0/240
7	SAT-PC	Post MSL1 260C	Pre and Post PC	3 lots x 5 units	0/15
* one unit lost between 500hrs and 1008hrs testing.					

ELECTRICAL CHARACTERISTIC SUMMARY:

There is no change in the electrical performance. Datasheet specifications remain unchanged.

CHANGED PART IDENTIFICATION:

Affected products with date code WW36-2012 and greater may be sourced from either Gresham or Aizu wafer Fabrication site.

**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16864****List of affected General Parts:**

MC33368DG
MC33368DR2G
NCP1203D100R2G
NCP1203D40R2G
NCP1203D60R2G
NCP1203P100G
NCP1203P40G
NCP1203P60G
NCP1207ADR2G
NCP1207APG
NCP1207BDR2G
NCP1216AD100R2G
NCP1216AD133R2G
NCP1216AD65R2G
NCP1216AP100G
NCP1216AP133G
NCP1216AP65G
NCP1216D100R2G
NCP1216D133R2G
NCP1216D65R2G
NCP1216P100G
NCP1216P133G
NCP1216P65G
NCP1217AD100R2G
NCP1217AD133R2G
NCP1217AD65R2G
NCP1217AP100G
NCP1217AP133G
NCP1217AP65G
NCP1217D100R2G
NCP1217D133R2G
NCP1217D65R2G
NCP1217P100G
NCP1217P133G
NCP1217P65G
NCP1377BD1R2G
NCP1377BDR2G
NCP1377BPG
NCP1377D1R2G
NCP1377DR2G
NCP1377PG
NCP1650DR2G
NCP1651DR2G